

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant

BEVAN et al.

Confirmation No: 5427

Appl. No.

10/633,517

Filed Title

: August 5, 2003

: ANALYTICAL METHOD AND APPARATUS THEREFOR

TC/A.U.

: 1743

Examiner

: Y. Gakh

Docket No.:

: BEVA3004D/REF

Customer No:

: 23364

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

This Supplemental Information Disclosure Statement is being submitted in the above-identified patent application to correct an obvious error in the Country/Agency listed for reference EP 0 345 782 A in that WIPO was listed instead of EP. Also attached herewith is the Form PTO-1449 with the correct Country/Agency listed.

In addition, the present application is a divisional application and the reference cited form recently received in the parent application is submitted herewith for the convenience of the Examiner and to update the present application. In accordance with MPEP §609, a Form 1449 listing this reference is also submitted herewith. Confirmation that the corrected prior art cited above and the newly cited reference in the parent application has been considered in the next Official Action is most respectfully requested.

Respectfully submitted, BACON & THOMAS, PLLC

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December 9, 2003

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	DEC U 3 5003 M					Sheet	1 of1	
B/O Form PT	0-1449	Atty. Docket Nu BE	umber EVA3004D/REF	Serial I	Vumber 1	0/633,51	7	
U.S. Pat	Department of Commerce and Trademark Office	Applicant BEVAN et a	Applicant BEVAN et al.				-	
Information	Disclosure Statement by Applicant	Filing Date	Group 1743					
	U.S. Patent Documents							
Examiner Initial	Document Number	Date	Patentee/Applicant		Class	Subclass	Filing Date if Appropriate	
	3,732,164	05/1973	Pressley et al.		210	752		

Foreign Patent Documents

Examiner					Subclass	Translation	
Initial	Document Number	Publication Date	Country/Agency	Class		Yes	No
	0 345 782 A	12/13/89	EP				
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Othe	r Documents (Including Author, Title, Date, Pertinent Pages, Place of Publication, Etc.)
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Examiner	Date Considered
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EXAMINER: Initial if citation is considered, whether or no t citation is in conf ormance with MPEP 609; Draw a line through citation if no t in conformance and not considered. Include copy of this form with next communication to applicant.

DEC 0 9 2003 Applicant(s)/Patent Under Reexamination Application/Control No. 09/486,715 BEVAN ET AL. Notic of References Cited Examiner Art Unit Yelena G. Gakh, Ph.D. 1743

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,732,164	05-1973	Pressley et al.	210/752
	В	US-			
	С	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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